Electronic supplementary information

## A resistance change effect in perovskite CH<sub>3</sub>NH<sub>3</sub>PbI<sub>3</sub> films induced by ammonia

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Fig. S1 The cross section SEM image of the pristine perovskite MAPbI<sub>3</sub> film, which indicates that the thickness of the film is about 1  $\mu$ m.



Fig. S2 (a) Photograph of the four copper probes used to measure the sheet resistance of the perovskite MAPbI<sub>3</sub> film. The perovskite MAPbI<sub>3</sub> film was deposited on the insulating side of a  $1.5 \times 1.5$  cm<sup>2</sup> FTO glass. (b) During the measurement the probes were pressed to contact with the film. (c) Before the NH<sub>3</sub> ON, the measured sheet resistance of the pristine film is 226 GΩ/sq. (d) When the NH<sub>3</sub> is ON, the sheet resistance of the film decreased to 1.47 GΩ/sq. (e) After the NH<sub>3</sub> was removed, the sheet resistance of the film restored to a high value of 97.1 GΩ/sq.



Fig. S3 (a) I-V curves of pristine perovskite MAPbI<sub>3</sub> in dry  $N_2$  and moist air with a relative humidity of around 50% and temperature of around 25 °C. (b) I-t curve of the MAPbI<sub>3</sub> film when posited in dry  $N_2$  and moist air alternatively with the applied voltage of 3 V.